



CLL Series Ultra Low Inductance Capacitors

Type:

CLLC1A CLLE1A

Issue date:

April 2011

TDK MLCC US Catalog

Version B11

REMINDERS

Please read before using this product

SAFETY REMINDERS

- 1. If you intend to use a product listed in this catalog for a purpose that may cause loss of life or other damage, you must contact our company's sales window.
- 2. We may modify products or discontinue production of a product listed in this catalog without prior notification.
- 3. We provide "Delivery Specification" that explain precautions for the specifications and safety of each product listed in this catalog. We strongly recommend that you exchange these delivery specifications with customers that use one of these products.
- 4. If you plan to export a product listed in this catalog, keep in mind that it may be a restricted item according to the "Foreign Exchange and Foreign Trade Control Law". In such cases, it is necessary to acquire export permission in harmony with this law.
- 5. Any reproduction or transferring of the contents of this catalog is prohibited without prior permission from our company.
- 6. We are not responsible for problems that occur related to the intellectual property rights or other rights of our company or a third party when you use a product listed in this catalog. We do not grant license of these rights.
- 7. This catalog only applies to products purchased through our company or one of our company's official agencies. This catalog does not apply to products that are purchased through other third parties.



CLL Series

Ultra Low Inductance Capacitors Type: CLLC1A (C1608), CLLE1A (C2012)



· Features a unique internal structure that cancels magnetic fields to reduce equivalent series inductance · Eight side terminal electrodes in one capacitor



- Decoupling CPU power line
- · High speed digital IC/decoupling
- GPU/CPU

Structure

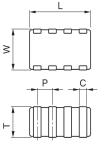


|--|--|

	U	LI	FLIP	STD
Chip Size	C1608	C2012	C1632	C2012
Cap.	1µF	1µF	1µF	1µF
W.V.	0G (4V)	0G (4V)	1A (10V)	1A (10V)
ESL	65pH	70pH	180pH	850pH









L	Body Length
W	Body Width
Т	Body Height
С	Terminal Width
Ρ	Terminal Spacing

Dimensions in mm

Part Nur Constru
Constru

Part Number
Construction

			CLLC1A	X7R	<u>0</u> J	105	м	Ţ	XXXX			
Series Name -										Internal Codes		
Case Code	Length	Width								Packaging Style		
CLLC1A	1.60 ± 0.10	0.80 ± 0.10									Ohda	
CLLE1A	2.00 ± 0.15	1.25 ± 0.15								Packaging Code	Style	
											Tape & Reel	
Temperature Ch	aracteristic —									Capacitance Tole	rance	
Temperature	Capacitance	Temperature								Tolerance Code	Tolerance	
Characteristics	Change	Range								Μ	± 20%	
X7R	± 15%	-55 to +125°C								Nominal Capacitance (pF)		
X7S	± 22%	-55 to +125°C								•	u ,	
Rated Voltage (I	DC)									•	is expressed in three s of pico Farads (pF).	0
Voltage Code	Voltage (DC)									and second digits	identify the first and	second
0G	4V									significant figures	of the capacitance.	The third
0J	6.3V									digit identifies the	multiplier. R designa	ites a
1A	10V									decimal point.		
										Capacitance Code	Capacitance	

Capacitance Code	Capacitance
0R5	0.5pF
010	1pF
102	1,000pF (1nF)
105	1,000,000pF (1µF)

②TDK

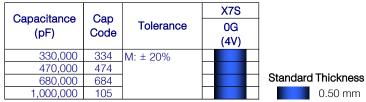
MULTILAYER CERAMIC CHIP CAPACITORS



CLLC1A [EIA CC0603]

Capacitance Range Chart

Temperature Characteristics: X7S (\pm 22) Rated Voltage: 4V (0G)





CLLC1A [EIA CC0603]

Class 2 (Temperature Stable)

Temperature Characteristics: X7S (-55 to +125°C, ±22%)

TDK Part Number (Ordering Code)	Temperature Characteristics	Rated Voltage	Capacitance (pF)	Capacitance Tolerance	Thickness (mm)
CLLC1AX7S0G334M	X7S	4V	330,000	± 20%	0.50 ± 0.10
CLLC1AX7S0G474M	X7S	4V	470,000	± 20%	0.50 ± 0.10
CLLC1AX7S0G684M	X7S	4V	680,000	± 20%	0.50 ± 0.10
CLLC1AX7S0G105M	X7S	4V	1,000,000	± 20%	0.50 ± 0.10

②TDK

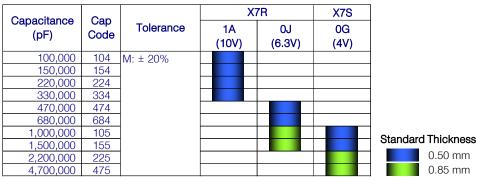
MULTILAYER CERAMIC CHIP CAPACITORS



CLLE1A [EIA CC0805]

Capacitance Range Chart

Temperature Characteristics: X7R (± 15%), X7S (± 22) Rated Voltage: 10V (1A), 6.3V (0J), 4V (0G)





Capacitance Range Table

CLLE1A [EIA CC0805]

Class 2 (Temperature Stable)

Temperature Characteristics: X7R (-55 to +125°C, ±15%), X7S (-55 to +125°C, ±22%)

TDK Part Number (Ordering Code)	Temperature Characteristics	Rated Voltage	Capacitance (pF)	Capacitance Tolerance	Thickness (mm)
CLLE1AX7R1A104M	X7R	10V	100,000	± 20%	0.50 ± 0.10
CLLE1AX7R1A154M	X7R	10V	150,000	± 20%	0.50 ± 0.10
CLLE1AX7R1A224M	X7R	10V	220,000	± 20%	0.50 ± 0.10
CLLE1AX7R1A334M	X7R	10V	330,000	± 20%	0.50 ± 0.10
CLLE1AX7R0J474M	X7R	6.3V	470,000	± 20%	0.50 ± 0.10
CLLE1AX7R0J684M	X7R	6.3V	680,000	± 20%	0.50 ± 0.10
CLLE1AX7R0J105M	X7R	6.3V	1,000,000	± 20%	0.85 ± 0.10
CLLE1AX7R0J155M	X7R	6.3V	1,500,000	± 20%	0.85 ± 0.10
CLLE1AX7S0G105M	X7S	4V	1,000,000	± 20%	0.50 ± 0.10
CLLE1AX7S0G155M	X7S	4V	1,500,000	± 20%	0.50 ± 0.10
CLLE1AX7S0G225M/0.50	X7S	4V	2,200,000	± 20%	0.50 ± 0.10
CLLE1AX7S0G225M/0.85	X7S	4V	2,200,000	± 20%	0.85 ± 0.10
CLLE1AX7S0G475M	X7S	4V	4,700,000	± 20%	0.85 ± 0.10

MULTILAYER CERAMIC CHIP CAPACITORS



General Specifications

No.	ltem	Performance	Test or Inspection Method			
1	External Appearance	No defects which may affect performance.	Inspect with magnifying glass (3 $ imes$).			
2	Insulation Resistance	100MΩ•μF min.	Apply rated voltage for 60s. Measure 8 terminal electrodes at the same time.			
3	Voltage Proof	Withstand test voltage without insulation breakdown or other damage.	2.5 times rated voltage (DC) shall be applied for 1 to 5s. Charge / discharge current shall not exceed 50mA. Measure 8 terminal electrodes at the same time.			
4	Capacitance	Within the specified tolerance at 1000hrs age (Per IEC-384-9).	Measuring Withstanding Measuring Frequency Voltage voltage			
			1kHz ± 10% 10V 1.0 ± 0.2 V _{rms} ≤ 6.3V 0.5 ± 0.2 V _{rms}			
			Measure 8 terminal electrodes at the same time.			
5	Dissipation Factor (Class 2)	T.C. D.F. X7R 0.10 max.	See No.4 in this table for measuring condition.			
6	Temperature Characteristics of Capacitance (Class 2)	Capacitance Change (%) No DC Voltage Applied X7R: ± 15%	Capacitance shall be measured by the steps shown in the following table after thermal equilibrium is obtained for each step. ΔC be calculated ref. STEP 3 reading			
	()	X7S: ± 22%	Step Temperature (°C)			
			1 Reference temp. ± 2 2 Min. operating temp. ± 2 3 Reference temp. ± 2 4 Max. operating temp. ± 2			
7	Robustness of Terminations	No sign of termination coming off, breakage of ceramic, or other abnormal signs.	Reflow solder the capacitor on P.C. board (shown in Appendix 1 and 2) and apply a pushing force of 2N for $10\pm1s$.			
8	Solderability	All terminations shall exhibit a continuous solder coating free from defects for a minimum of 75% of the surface area of any individual termination. Anomalies other than dewetting, non-wetting, and pin holes are not cause for rejection. Ceramic surface of A sections shall not be exposed due to melting or shifting of termination material.	Completely soak both terminations in solder at 235±5°C for 2±0.5s. Solder : H63A (JIS Z 3282) Flux : Isopropyl alcohol (JIS K 8839) Rosin (JIS K 5902) 25% solid solution.			

MULTILAYER CERAMIC CHIP CAPACITORS



No.	ltem	Performance		Test or	r Inspection Method		
9	Resistance to sold	er heat		Completely soak both terminations in solder at $260\pm5^{\circ}$ C for 5 ± 1 s.		in solder at	
	External appearance		No cracks are allowed and terminations shall be covered at least 60% with new solder		Preheating condition Temp. : 150±10°C		
	Capacitance	Characteristics	Change from the value before test		e :1 to 2min. opropyl alcohol (JIS K 8839)	
		X7R X7S	± 7.5 %		osin (JIS K 5902) 25% solid		
	D.F. (Class 2)	Meet the initial sp	ec.		H63A (JIS Z 3282) ne capacitor in ambient cond	ditions for $24 + 2h$	
	Insulation Resistance	Meet the initial sp	ec.		neasurement.		
10	Vibration			Reflow solder the capacitor on a P.C. board (shown in Appendix 1 and 2) before testing.			
	External appearance	No mechanical da	No mechanical damage.		Vibrate the capacitor with amplitude of 1.5mm P-P		
	Capacitance	Characteristics	Change from the value before test	 sweeping the frequencies from 10Hz to 55Hz and back to 10Hz in about 1 minute. 			
		X7R X7S	± 7.5 %	Repeat this for 2h each in 3 perpendicular directions (6h in total).			
	D.F. (Class 2)	Meet the initial sp	ec.	-			
11	Temperature cycle	•		Reflow solder the capacitors on a P.C. board (shown in Appendix 1 and 2) before testing. Expose the capacitor in the condition step1 through			
	External appearance	No mechanical da	amage.				
	Capacitance	Characteristics	Change from the value before test	step 4, and repeat 5 times Leave the capacitor in amb		2	
		X7R X7S	± 7.5 %		neasurement.		
				Step	Temperature (°C)	Time (min.)	
	D.F. (Class 2)	Meet the initial sp	ec.	2	Min. operating temp. ±3 Reference Temp.	30 ± 3 $2 - 5$	
	Insulation	Meet the initial sp	ec.	3	Max. operating temp. ± 2	30 ± 2	
	Resistance	·		4	Reference Temp.	2 - 5	
	Voltage Proof	No insulation breakdown or other damage.				·	

MULTILAYER CERAMIC CHIP CAPACITORS



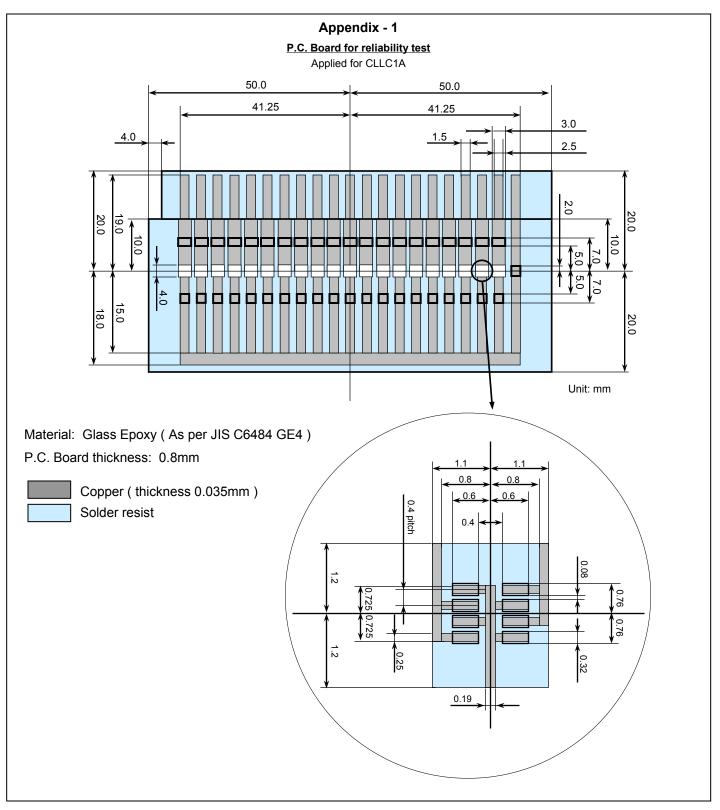
General Specifications

No.	ltem	Performance		Test or Inspection Method			
12	Moisture Resistance (Steady State) External No mechanical damage. appearance		amage.	Reflow solder the capacitor on P.C. board (shown in Appendix 1 and 2) before testing. Leave at temperature 40±2°C and 90 to 95%RH for			
	Capacitance	Characteristics	Change from the value before test	= 500 + 24,0h. Leave the capacitor in ambient condition for 24±2h			
		X7R X7S	± 12.5 %	before measurement.			
	D.F. (Class 2)	Characteristics: X7R: 200% of init X7S: 200% of init	-				
	Insulation Resistance	10MΩ·μF min.					
13	Moisture Resistance			Reflow solder the capacitors on P.C. board (shown in			
	External appearance			Appendix 1 and 2) before testing. Apply the rated voltage at temperature 40±2°C and 90 to 95%RH for 500 +24,0h.			
	Capacitance	Characteristics	Change from the value before test	Charge/discharge current shall not exceed 50mA.			
		X7R X7S	± 12.5 %	Leave the capacitor in ambient conditions for $48\pm4h$ before measurement.			
	D.F. (Class 2)	Characteristics X7R: 200% of init X7S: 200% of init	•	Voltage conditioning: Voltage treat the capacitors under testing temperatu and voltage for 1 hour.			
	Insulation Resistance	5MΩ·μF min.		Leave the capacitors in ambient condition for $24\pm 2h$ before measurement.			
				Use this measurement for initial value.			
14	Life External	No mochanical d	27220	Reflow solder the capacitor on P.C. board (shown in Appendix 1 and 2) before testing.			
	appearance	No mechanical da	anage.	Apply 1 x rated voltage at $125\pm2^{\circ}$ C for 1,000 +48, 0h.			
	Capacitance	Characteristics	Change from the value before test	Charge/discharge current shall not exceed 50mA.			
		X7R X7S	± 15 %	Leave the capacitors in ambient condition for $24\pm 2h$ before measurement.			
	D.F. (Class 2)	Characteristics X7R: 200% of initial spec. max. X7S: 200% of initial spec. max.		 Voltage conditioning: Voltage treat the capacitor under testing temperature and voltage for 1 hour. 			
	Insulation Resistance	10MΩ·µF min.		 Leave the capacitor in ambient conditions for 48±4h before measurement. 			
				Use this measurement for initial value.			

MULTILAYER CERAMIC CHIP CAPACITORS



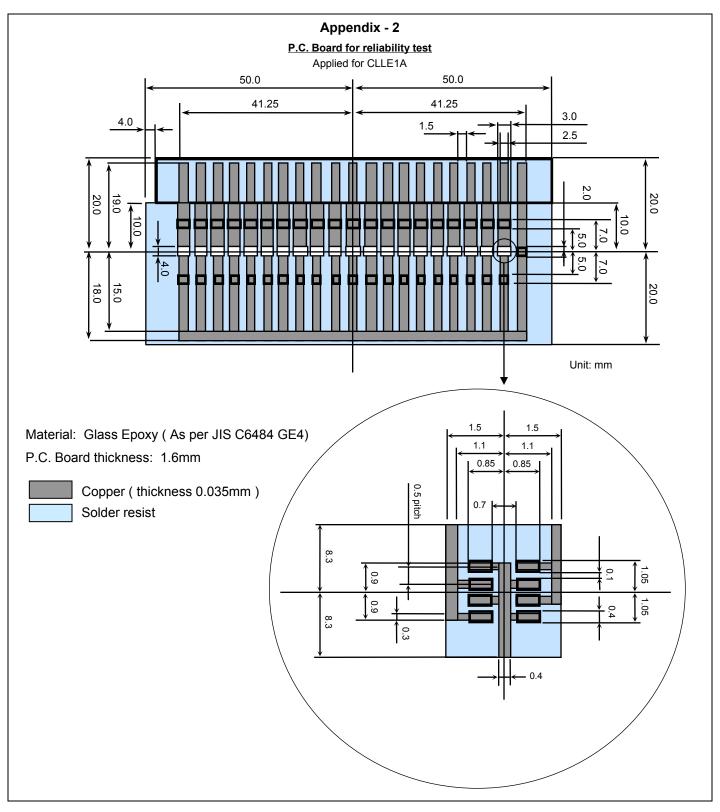
General Specifications



MULTILAYER CERAMIC CHIP CAPACITORS



General Specifications

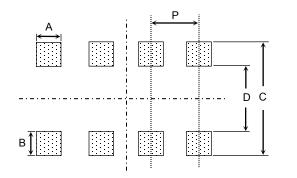


②TDK

MULTILAYER CERAMIC CHIP CAPACITORS

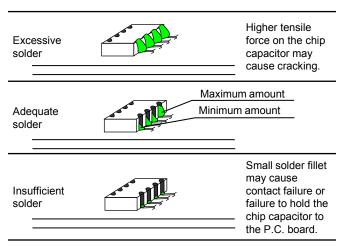


Recommended Soldering Land Pattern



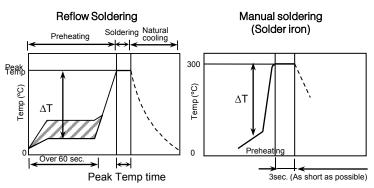
Reflow Soldering		Unit: mm	
Туре	CLLC1A	CLLE1A	
Symbol	(C1608/CC0603)	(C2012/CC0805)	
А	0.25	0.3	
В	0.4	0.3 ~ 0.6	
С	1.2	1.3 ~ 1.8	
D	0.4	0.5 ~ 0.8	
Р	0.4	0.5	

Recommended Solder Amount



CLL Series – ULI Capacitors

• Recommended Soldering Profile



Recommended soldering duration

Temp./	Reflow S	oldering	
Dura. Solder	Peak temp (°C)	Duration (sec.)	
Sn-Pb Solder	230 max.	20 max.	
Lead-Free Solder	260 max.	10 max.	

Recommended solder compositions Sn-37Pb (Sn-Pb solder) Sn-3.0Ag-0.5Cu (Lead Free Solder)

Preheating Condition

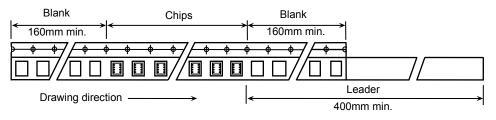
Soldering	Temp. (°C)
Reflow soldering	∆T ≤ 150
Manual soldering	∆T ≤ 150

MULTILAYER CERAMIC CHIP CAPACITORS

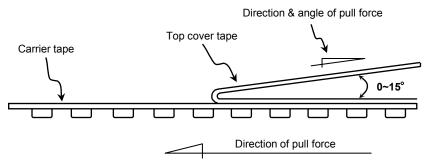


CLL Series – ULI Capacitors

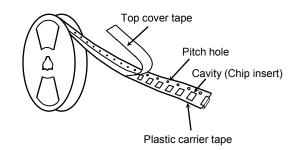
Carrier Tape Configuration



• Peel Back Force (Top Tape)



Chip Quantity Per Reel and Structure of Reel



Series	Taping	Chip quantity (pcs.)		
	Material	φ178mm (7") reel	φ330mm (13") reel	
CLLC1A	Plastic	4,000	10,000	
CLLE1A	Plastic	4,000	10,000	

• Carrier tape shall be flexible enough to be wound around a minimum radius of 30mm with components in tape.

 \bullet The missing of components shall be less than 0.1%

• Components shall not stick to the cover tape.

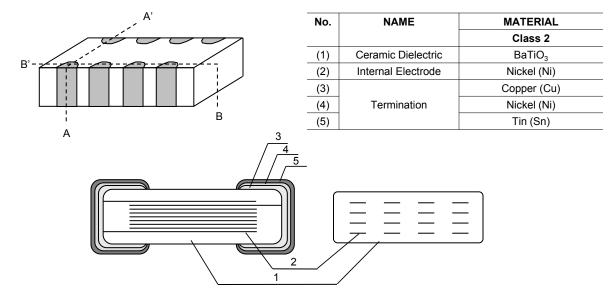
• The cover tape shall not protrude beyond the edges of the carrier tape and shall not cover the sprocket holes.

MULTILAYER CERAMIC CHIP CAPACITORS

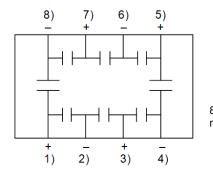


CLL Series – ULI Capacitors

Inside Structure & Material System



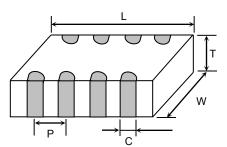
• Equivalent Circuit



+ 1) 3) 5) 7) - 2) 4) 6) 8)

8 terminals are connected and measured at the same time.

Shape & Dimensions



Case Code		Dimensions (mm)					
Series	JIS	EIA	L	w	Т	Р	С
CLLC1A	C1608	CC0603	1.60	0.80	0.55 max.	0.40	0.25
CLLE1A	C2012	CC0805	2.00	1.25	0.95 max.	0.50	0.25

Environmental Information

TDK Corporation established internal product environmental assurance standards that include the six hazardous substances banned by the EU RoHS Directive¹ enforced on July 1, 2006 along with additional substances independently banned by TDK and has successfully completed making general purpose electronic components conform to the RoHS Directive².

- Abbreviation for Restriction on Hazardous Substances, which refers to the regulation EU Directive 2002/95/EC on hazardous substances by the European Union (EU) effective from July 1, 2006. The Directive bans the use of six specific hazardous substances in electric and electronic devices and products handled within the EU. The six substances are lead, mercury, cadmium, hexavalent chromium, PBB (polybrominated biphenyls), and PBDE (polybrominated diphenyl ethers).
- This means that, in conformity with the EU Directive 2002/95/EC, lead, cadmium, mercury, hexavalent chromium, and specific bromine-based flame retardants, PBB and PBDE, have not been used, except for exempted applications.
- For REACH (SVHC : 15 substances according to ECHA / October 2008) : All TDK MLCC do not contain these 15 substances.
- For European Directive 2000/53/CE and 2005/673/CE : Cadmium, Hexavalent Chromium, Mercury, Lead are not contained in all TDK MLCC.
- For European Directive 2003/11/CE : Pentabromodiphenylether, Octabromodiphenyl-ether are not contained in all TDK MLCC.